

**Search Notes**

Application/Control No.

10/602,848

Examiner

W. Patty Chen

Applicant(s)/Patent under  
Reexamination

TANAKA ET AL.

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner
349	40	9/28/2006	WPC
349	147	9/28/2006	WPC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Citations search of relevant references	9/28/2006	WPC
349/147 combined with 349/148 search of all databases in EAST	9/28/2006	WPC
349/147 combined with 349/152 search of all databases in EAST	9/28/2006	WPC
349/152 combined with 349/148 search of all databases in EAST	9/28/2006	WPC
349/147-152 combined with key words search of all databases in EAST	9/28/2006	WPC
Consulted Primary Examiner Andrew Schechter in interpreting claims	9/28/2006	WPC